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(12)

United States Design Patent

Kang et al.

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(54) SEAL MEMBER FOR USE IN SEMICONDUCTOR PRODUCTION APPARATUS

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(73) Assignee: Valqua, Ltd., Tokyo (JP)

(**) Term: 15 Years

(21) Appl. No.: 29/714,181

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Related U.S. Application Data

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Foreign Application Priority Data

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(52) U.S. Cl.

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CPC	F16J 15/025 (2013.01)

(58) Field of Classification Search

USPC	D15/7, 9, 11, 17, 21, 28, 123, 199; D23/269, 386, 259; D8/349; 277/602–626; 285/95, 109, 336, 910, 918
CPC	F16K 51/02; F16J 15/025; F16J 15/0887; F16J 15/104; F16J 15/128

See application file for complete search history.

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(57) CLAIM

The ornamental design for a seal member for use in semiconductor production apparatus, as shown and described.

DESCRIPTION

FIG. 1 is a perspective view of a seal member for use in semiconductor production apparatus, showing our new design;

FIG. 2 is a front elevation view thereof;

FIG. 3 is a rear elevation view thereof;

FIG. 4 is a left side elevation view thereof;

FIG. 5 is a right side elevation view thereof;

FIG. 6 is a top view thereof;

(Continued)

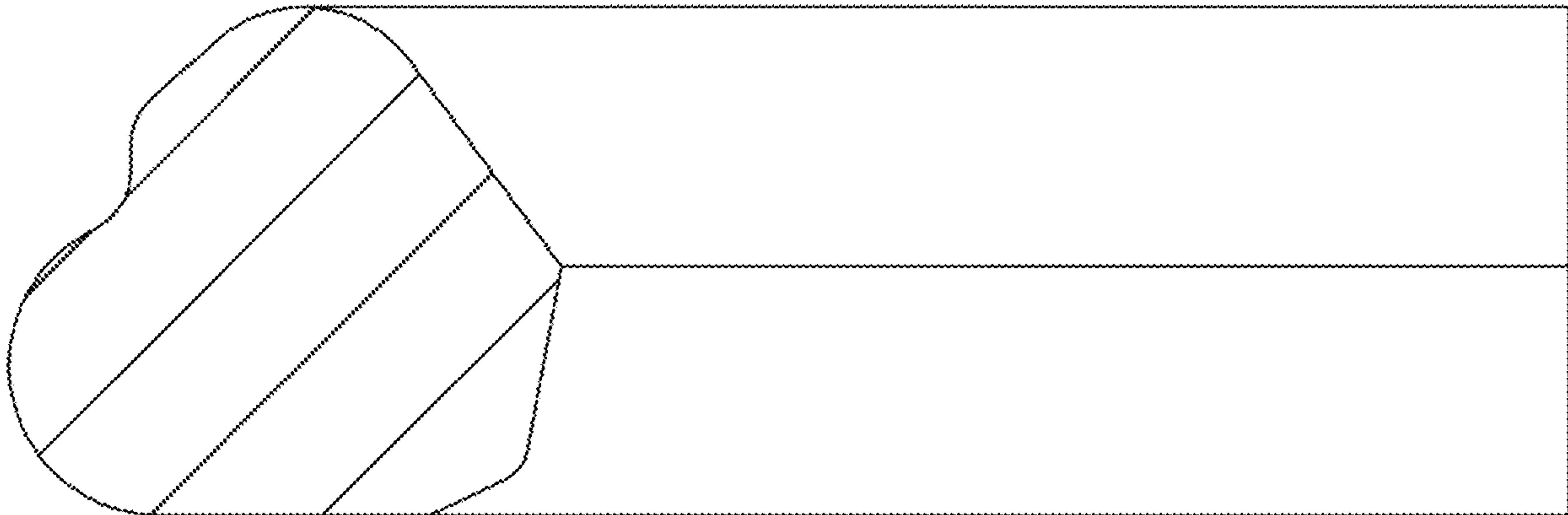


FIG. 7 is a bottom view thereof;
FIG. 8 is a cross-sectional view thereof; and,
FIG. 9 is an enlarged cross-sectional view of a portion thereof.

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1 Claim, 9 Drawing Sheets

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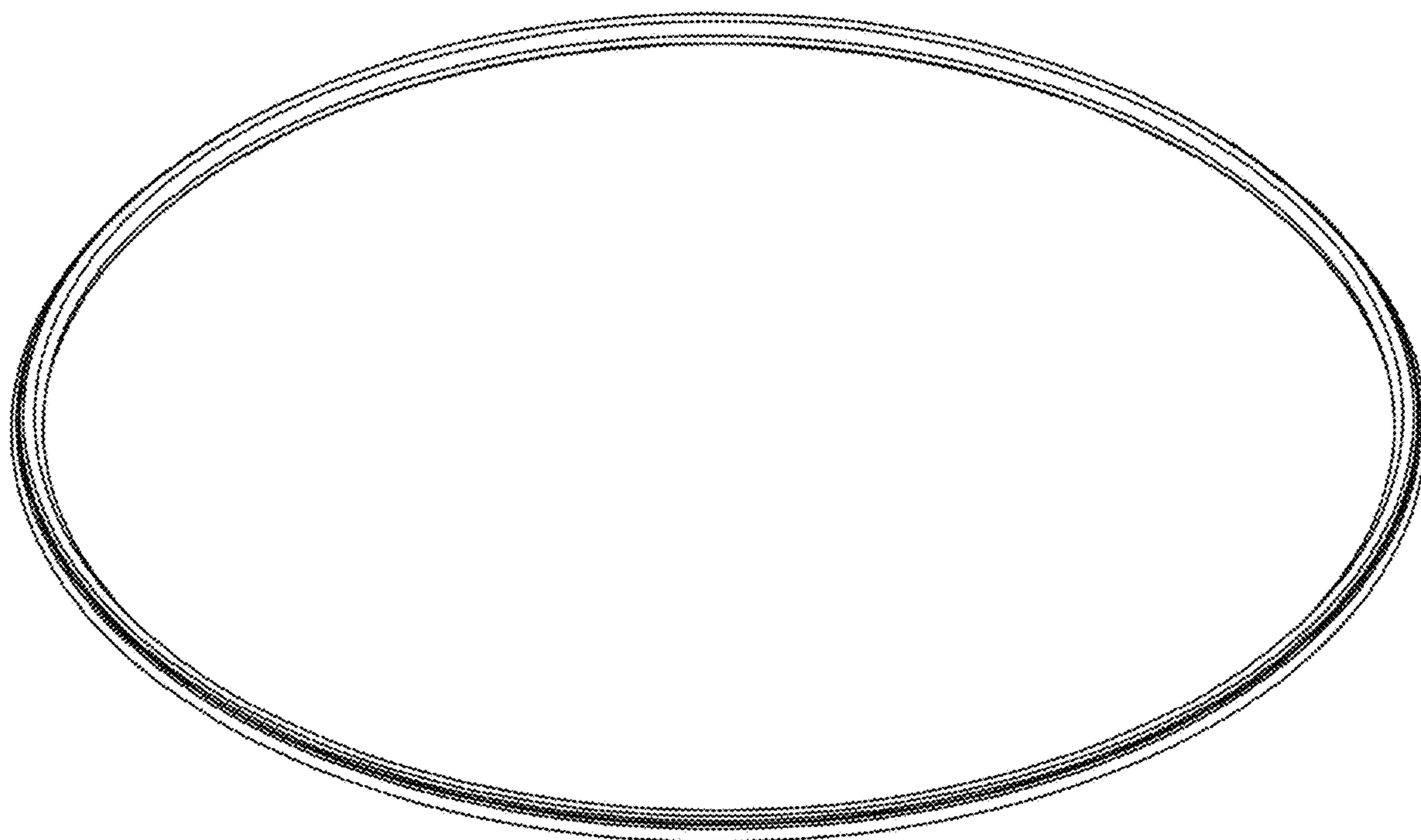


FIG. 1



FIG. 2



FIG. 3



FIG. 4



FIG. 5

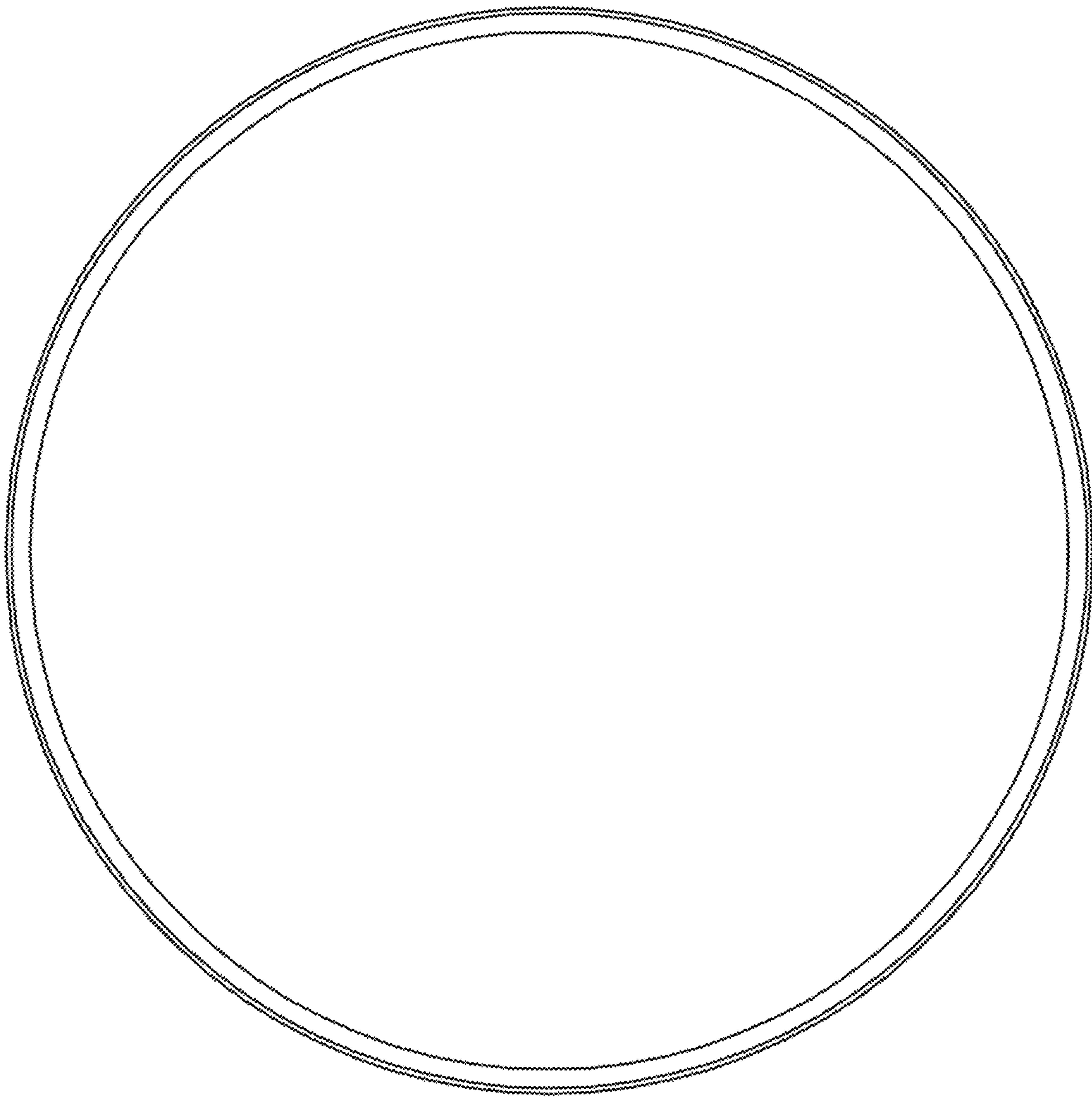


FIG. 6

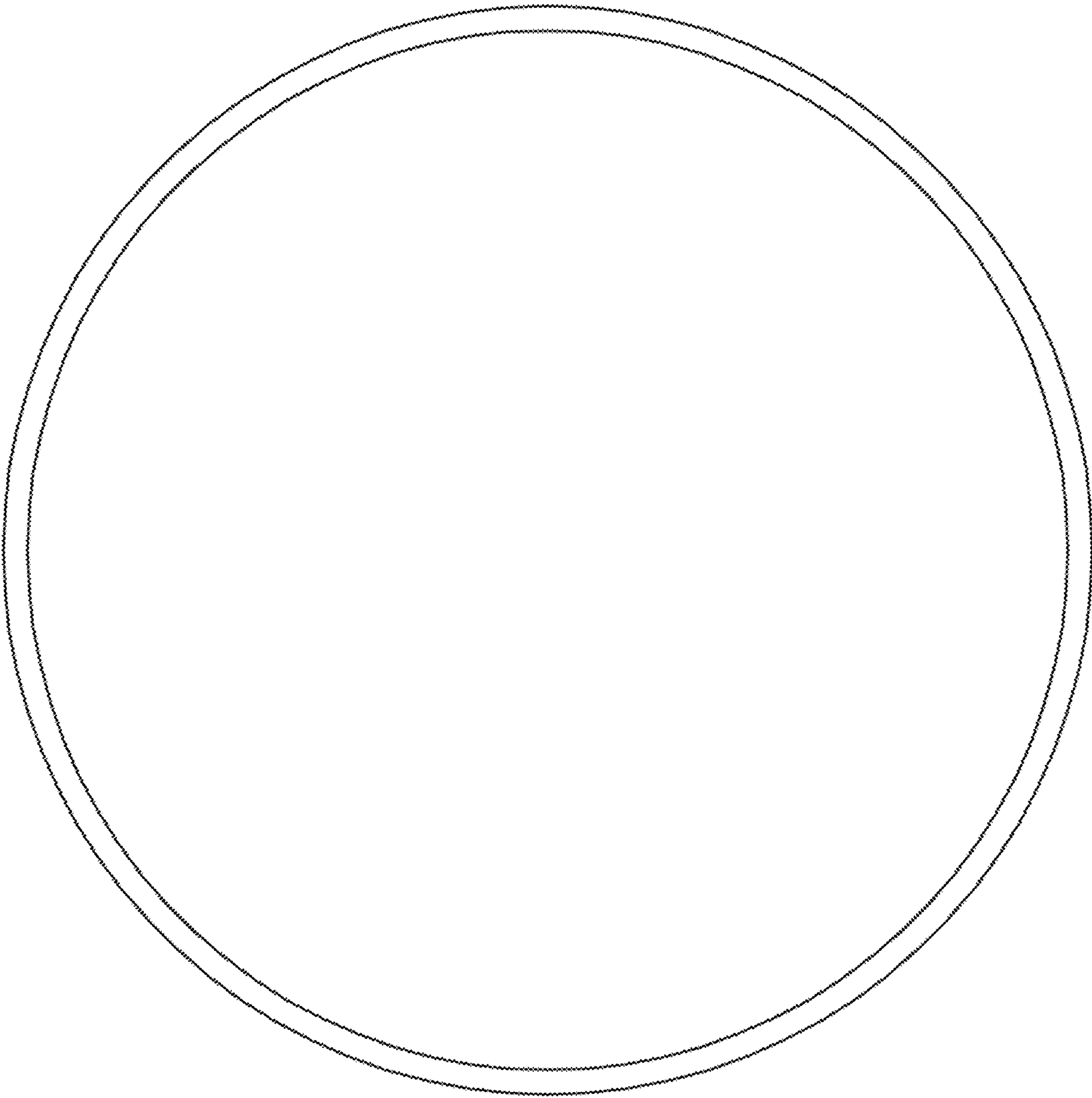


FIG. 7

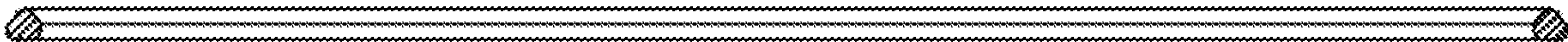


FIG. 8

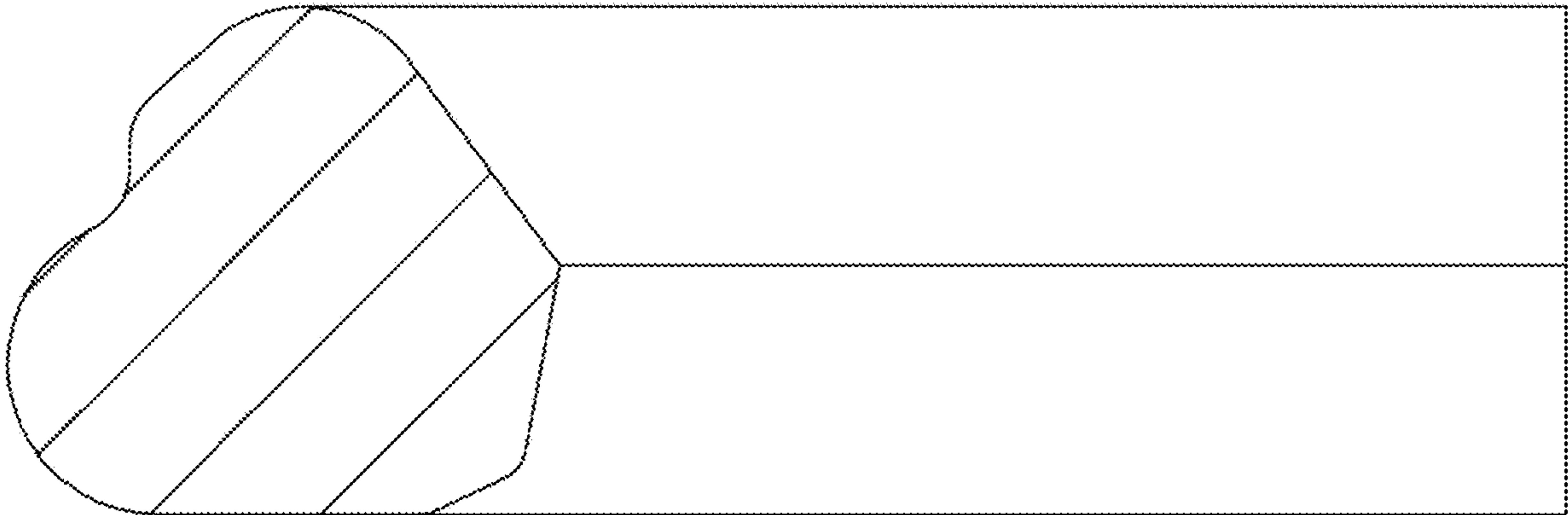


FIG. 9